Power MOSFET

30 V, 58 A, Single N-Channel, DPAK/IPAK

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- AEC-Q101 Qualified and PPAP Capable NVD4809NH
- These Devices are Pb-Free and are RoHS Compliant

Applications

- CPU Power Delivery
- DC-DC Converters
- Low Side Switching

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Param	Symbol	Value	Unit		
Drain-to-Source Voltag	V _{DSS}	30	V		
Gate-to-Source Voltage	Gate-to-Source Voltage				V
Continuous Drain		T _A = 25°C	I _D	11.5	Α
Current (R _{θJA}) (Note 1)		T _A = 85°C		9.0	
Power Dissipation $(R_{\theta JA})$ (Note 1)		T _A = 25°C	P _D	2.0	W
Continuous Drain		T _A = 25°C	I _D	9.0	Α
Current (R _{θJA}) (Note 2)	Steady	T _A = 85°C		7.0	
Power Dissipation $(R_{\theta JA})$ (Note 2)	State	T _A = 25°C	P _D	1.3	W
Continuous Drain		T _C = 25°C	I _D	58	Α
Current (R ₀ JC) (Note 1)		T _C = 85°C		45	
Power Dissipation $(R_{\theta JC})$ (Note 1)		T _C = 25°C	P _D	52	W
Pulsed Drain Current	t _p =10μs	T _A = 25°C	I _{DM}	130	Α
Current Limited by Packa	age	T _A = 25°C	I _{DmaxPkg}	45	Α
Operating Junction and S	T _J , T _{stg}	–55 to 175	°C		
Source Current (Body Di	I _S	43	Α		
Drain to Source dV/dt	dV/dt	6.0	V/ns		
Single Pulse Drain-to-Source Avalanche Energy (V_{DD} = 24 V, V_{GS} = 10 V, L = 1.0 mH, $I_{L(pk)}$ = 15 A, R_G = 25 Ω)			E _{AS}	112.5	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

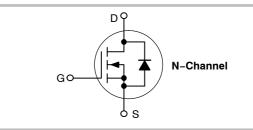
Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.



ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX	
30 V	9.0 mΩ @ 10 V	58 A	
30 V	12.5 mΩ @ 4.5 V	30 A	



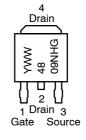


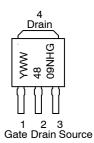




3 IPAK CASE 369AD (Straight Lead)

MARKING DIAGRAMS & PIN ASSIGNMENTS





Y = Year

WW = Work Week

4809NH= Device Code

G = Pb-Free Package

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 6 of this data sheet.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter		Value	Unit
Junction-to-Case (Drain)		2.9	°C/W
Junction-to-TAB (Drain)	$R_{ heta JC-TAB}$	3.5	
Junction-to-Ambient - Steady State (Note 1)	$R_{ heta JA}$	74	
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	116	

- Surface-mounted on FR4 board using 1 in sq pad size, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size.

ELECTRICAL CHARACTERISTICS (T₁ = 25°C unless otherwise noted)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•				•		
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0 V, I _D = 250 μA		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				25		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	T _J = 25°C			1.0	μΑ
		$V_{GS} = 0 \text{ V},$ $V_{DS} = 24 \text{ V}$	T _J = 125°C			10	1
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V	_{GS} = ±20 V			±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}$,	I _D = 250 μA	1.5	2.1	2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.7		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 to	I _D = 30 A		7.0	9.0	mΩ
		11.5 V	I _D = 15 A		7.0		1
		V _{GS} = 4.5 V	I _D = 30 A		10.45	12.5	1
		I _D = 15 A			9.95		1
Forward Transconductance	9 _{FS}	V _{DS} = 15 V, I _D = 15 A			9.0		S
CHARGES AND CAPACITANCES							
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V, f} = 1.0 \text{ MHz,}$ $V_{DS} = 12 \text{ V}$			1596	2155	pF
Output Capacitance	C _{oss}				331	447	
Reverse Transfer Capacitance	C _{rss}				190	294	1
Total Gate Charge	Q _{G(TOT)}				12.5	15	nC
Threshold Gate Charge	Q _{G(TH)}	V _{GS} = 4.5 V, V _{DS} = 15 V, I _D = 30 A			2.4	3.6	1
Gate-to-Source Charge	Q_{GS}	I _D = 3	30 Å		5.3	7.9	1
Gate-to-Drain Charge	Q_{GD}				5.1	7.7	1
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 11.5 V, V _{DS} = 15 V, I _D = 30 A			29.3	44	nC
SWITCHING CHARACTERISTICS (Note 4)							
Turn-On Delay Time	t _{d(on)}				12.0	18	ns
Rise Time	t _r	V_{GS} = 4.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			20	30	1
Turn-Off Delay Time	t _{d(off)}				14	21	1
Fall Time	t _f				5.0	7.5	1
Turn-On Delay Time	t _{d(on)}				7.0	10.4	ns
Rise Time	t _r	V _{GS} = 11.5 V	V _{DS} = 15 V.		18	27	1
Turn-Off Delay Time	t _{d(off)}	V_{GS} = 11.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			22	33	1
Fall Time	t _f		ľ		3.0	4.6	1

- 3. Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
- 4. Switching characteristics are independent of operating junction temperatures.

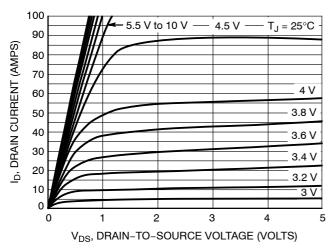
ELECTRICAL CHARACTERISTICS ($T_J = 25$ °C unless otherwise noted)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
DRAIN-SOURCE DIODE CHARACTERISTICS							
Forward Diode Voltage	V _{SD}	V _{GS} = 0 V,	$T_J = 25^{\circ}C$		0.95	1.2	V
		I _S = 30 A	T _J = 125°C		0.83		
Reverse Recovery Time	t _{RR}		•		15.6		ns
Charge Time	ta	V _{GS} = 0 V, dls/dt = 100 A/μs, I _S = 30 A			10.6		
Discharge Time	tb				5.0		
Reverse Recovery Time	Q _{RR}				7.5		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L _S				2.49		nΗ
Drain Inductance, DPAK	L _D				0.0164		
Drain Inductance, IPAK	L _D	T _A = 25°C			1.88		
Gate Inductance	L _G				3.46		
Gate Resistance	R _G				0.75		Ω

TYPICAL PERFORMANCE CURVES

80

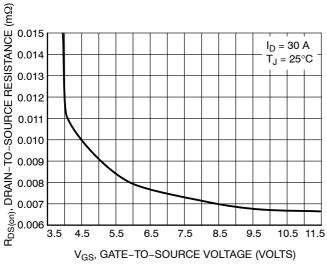
 $V_{DS} \ge 10 \text{ V}$



(S) 70 (S) Well 40 (S) Well 40 (S) Well 40 (S) To 10 (S) To 1

Figure 1. On-Region Characteristics

V_{GS}, GATE-TO-SOURCE VOLTAGE (VOLTS) Figure 2. Transfer Characteristics



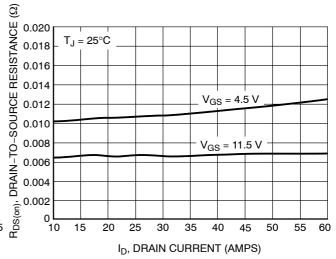
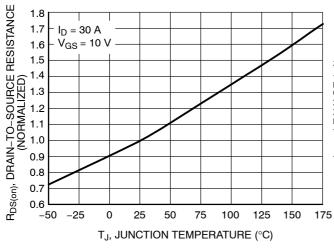


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



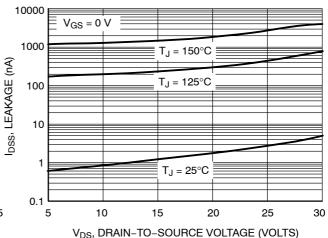


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Drain Voltage

TYPICAL PERFORMANCE CURVES

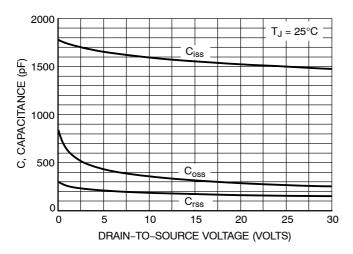


Figure 7. Capacitance Variation

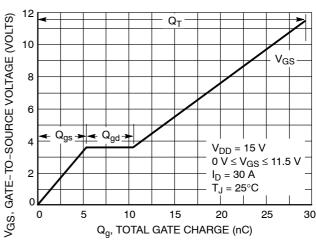


Figure 8. Gate-to-Source Voltage vs. Total Charge

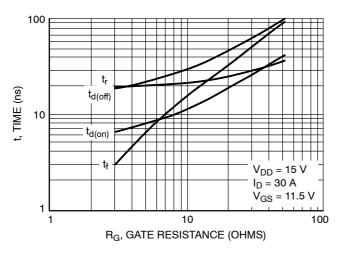


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

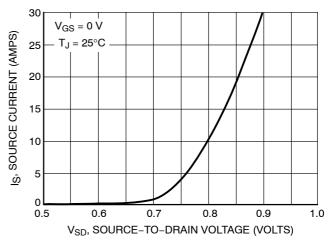


Figure 10. Diode Forward Voltage vs. Current

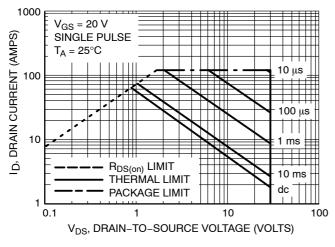


Figure 11. Maximum Rated Forward Biased Safe Operating Area

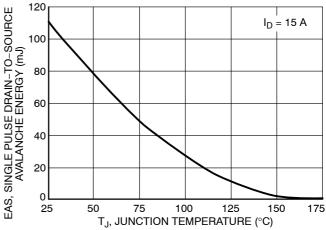


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL PERFORMANCE CURVES

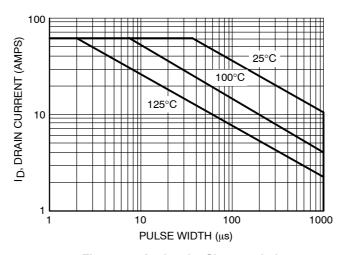


Figure 13. Avalanche Characteristics

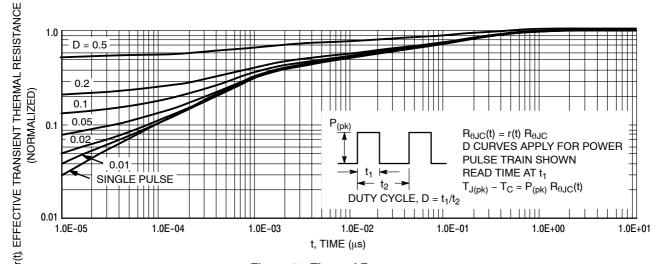


Figure 14. Thermal Response

ORDERING INFORMATION

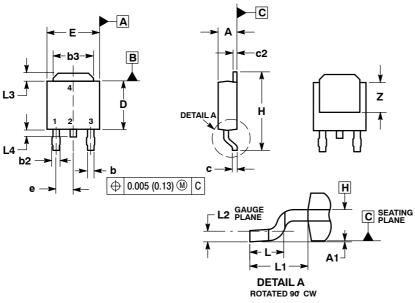
Device	Package	Shipping [†]
NTD4809NHT4G	DPAK (Pb-Free)	2500 / Tape & Reel
NTD4809NH-35G	IPAK Trimmed Lead (3.5 \pm 0.15 mm) (Pb-Free)	75 Units / Rail
NVD4809NHT4G	DPAK (Pb-Free)	2500 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

PACKAGE DIMENSIONS

DPAK (SINGLE GUAGE)

CASE 369AA-01 **ISSUE B**



NOTES:

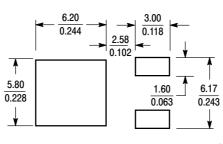
- 1. DIMENSIONING AND TOLERANCING PER ASME

- 1. DIMENSIONING AND TOLEHANCING PEH ASME Y14.5M, 1994.
 2. CONTROLLING DIMENSION: INCHES.
 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS b3, L3 and Z.
 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0,006 INCHES PER SIDE.
- 5. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 6. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

	INC	HES	MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	0.086	0.094	2.18	2.38	
A1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.030	0.045	0.76	1.14	
b3	0.180	0.215	4.57	5.46	
C	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
Е	0.250	0.265	6.35	6.73	
e	0.090	BSC	2.29	BSC	
Н	0.370	0.410	9.40	10.41	
L	0.055	0.070	1.40	1.78	
L1	0.108	REF	2.74 REF		
L2	0.020	BSC	0.51	BSC	
L3	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
Z	0.155		3.93		

STYLE 2: PIN 1. GATE 2. DRAIN 3. SOURCE 4. DRAIN

SOLDERING FOOTPRINT*



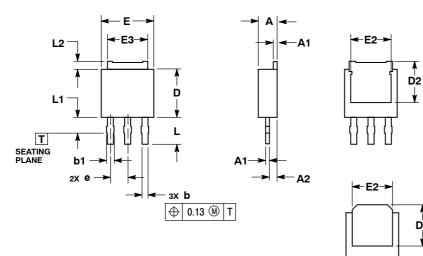
SCALE 3:1

^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

3.5 MM IPAK, STRAIGHT LEAD

CASE 369AD-01 **ISSUE A**



NOTES:

D₂

OPTIONAL CONSTRUCTION

- DIMENSIONING AND TOLERANCING PER
 ASME Y14.5M, 1994.
- CONTROLLING DIMENSION: MILLIMETERS.

 DIMENSION b APPLIES TO PLATED TERMINAL
- AND IS MEASURED BETWEEN 0.15 AND 0.30mm FROM TERMINAL TIP.
- DIMENSIONS D AND E DO NOT INCLUDE MOLD GATE OR MOLD FLASH.

	MILLIMETERS			
DIM	MIN MAX			
Α	2.19	2.38		
A1	0.46	0.60		
A2	0.87	1.10		
b	0.69	0.89		
b1	0.77	1.10		
D	5.97	6.22		
D2	4.80			
E	6.35	6.73		
E2	4.57	5.45		
E3	4.45	5.46		
е	2.28 BSC			
L	3.40	3.60		
L1		2.10		
L2	0.89	1.27		

ON Semiconductor and un are registered trademarks of Semiconductor Components Industries, LLC (SCILLC). SCILLC reserves the right to make changes without further notice on semiconductor and war engineer trademarks of semiconductor components industries, Ite (SciLLC) solitate services are injective to any products herein. SCILLC makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does SCILLC assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. "Typical" parameters which may be provided in SCILLC data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. SCILLC does not convey any license under its patent rights nor the rights of others. SCILLC products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the SCILLC product could create a situation where personal injury or death may occur. Should Buyer purchase or use SCILLC products for any such unintended or unauthorized application, Buyer shall indemnify and hold SCILLC and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that SCILLC was negligent regarding the design or manufacture of the part. SCILLC is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor P.O. Box 5163, Denver, Colorado 80217 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada

Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com

N. American Technical Support: 800-282-9855 Toll Free USA/Canada

Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910 Japan Customer Focus Center

Phone: 81-3-5817-1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative